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PTO/SB/17 (12-04v2)

Approved for use through 7/31/2006. OMB 0651-0032
U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no person are required to respond to a collection of information unless it displays a valid OMB control number.

Effective on 12/08/2004.

Fees pursuant to the Consolidated Appropriations Act, 2005 (H.R. 4818).

FEE TRANSMITTAL For FY 2005

Applicant claims small entity status. See 37 CFR 1.27

TOTAL AMOUNT OF PAYMENT (\$ 100.00)

Complete if Known

| | |
|----------------------|--------------------------|
| Application Number | Patent#: 6,961,277 |
| Filing Date | Issued: November 1, 2005 |
| First Named Inventor | John T. Moore |
| Examiner Name | V. Q. Nguyen |
| Art Unit | 2818 |

METHOD OF PAYMENT (check all that apply)

Check Credit Card Money Order None Other (please identify): _____
 Deposit Account Deposit Account Number: 04-1073 Deposit Account Name: Dickstein Shapiro Morin & Oshinsky LLP

For the above-identified deposit account, the Director is hereby authorized to: (check all that apply)

Charge fee(s) indicated below Charge fee(s) indicated below, except for the filing fee
 Charge any additional fee(s) or underpayment of Credit any overpayments

FEE CALCULATION

1. BASIC FILING, SEARCH, AND EXAMINATION FEES

| Application Type | FILING FEES | | SEARCH FEES | | EXAMINATION FEES | | Fees Paid (\$) |
|------------------|-------------|-----------------------|-------------|-----------------------|------------------|-----------------------|----------------|
| | Fee (\$) | Small Entity Fee (\$) | Fee (\$) | Small Entity Fee (\$) | Fee (\$) | Small Entity Fee (\$) | |
| Utility | 300 | 150 | 500 | 250 | 200 | 100 | |
| Design | 200 | 100 | 100 | 50 | 130 | 65 | |
| Plant | 200 | 100 | 300 | 150 | 160 | 80 | |
| Reissue | 300 | 150 | 500 | 250 | 600 | 300 | |
| Provisional | 200 | 100 | 0 | 0 | 0 | 0 | |

2. EXCESS CLAIM FEES

Fee Description

Each claim over 20 (including Reissues)

Small Entity
Fee (\$) Fee (\$)

50 25

Each independent claim over 3 (including Reissues)

200 100

Multiple dependent claims

360 180

Total Claims **Extra Claims** **Fee (\$)** **Fee Paid (\$)**

_____ - = _____ x _____ = _____

Multiple Dependent Claims
Fee (\$) Fee Paid (\$)

Indep. Claims **Extra Claims** **Fee (\$)** **Fee Paid (\$)**

_____ - = _____ x _____ = _____

3. APPLICATION SIZE FEE

If the specification and drawings exceed 100 sheets of paper (excluding electronically filed sequence or computer listings under 37 CFR 1.52(e)), the application size fee due is \$250 (\$125 for small entity) for each additional 50 sheets or fraction thereof. See 35 U.S.C. 41(a)(1)(G) and 37 CFR 1.16(s).

| | | | | |
|---------------------|---------------------|---|-----------------|----------------------|
| Total Sheets | Extra Sheets | Number of each additional 50 or fraction thereof | Fee (\$) | Fee Paid (\$) |
| _____ | - 100 = _____ | /50 (round up to a whole number) x _____ | = _____ | |

4. OTHER FEE(S)

Non-English Specification, \$130 fee (no small entity discount)

Other (e.g., late filing surcharge): 1811 Certificate of correction

100.00

SUBMITTED BY

| | | | | | |
|-------------------|---|--------------------------------------|--------|-----------|------------------|
| Signature |  | Registration No. (Attorney/Agent) | 28,371 | Telephone | (202) 828-2232 |
| Name (Print/Type) | Thomas J. D'Amico | | | Date | January 17, 2006 |

**Certificate
JAN 20 2006
of Correction**

FEB 1 2006



Docket No.: M4065.0715/P715
(PATENT)

THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Letters Patent of:
John T. Moore et al.

Patent No.: 6,961,277

Issued: November 1, 2005

For: METHOD OF REFRESHING A PCRAM
MEMORY DEVICE

REQUEST FOR CERTIFICATE OF CORRECTION
PURSUANT TO 37 C.F.R. §§ 1.322 & 1.323

Attention: Certificate of Correction Branch
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Upon reviewing the above-identified patent, Patentee noted omissions and typographical errors which should be corrected.

In the **U.S. Patent Documents** portion of the References Cited section, the USPTO omitted the listing of forty-nine patents. Exhibit A, attached, shows the IDS forms as considered and signed by the Examiner. The patents that should be added are as follows:

| 01/19/2006 MBEYENE1 00000039 6961277 | | | |
|--------------------------------------|---------|-----------------------------|-----------|
| 3,622,319 | 11/1971 | Sharp ³¹ FC:1811 | 100.00 OP |
| 3,743,847 | 7/1973 | Boland | |
| 4,269,935 | 5/1981 | Masters et al. | |

| | | |
|-----------|------------|------------------------|
| 4,312,938 | 1/1982 | Drexler, et al. |
| 4,316,946 | 1/1982 | Masters, et al. |
| 4,320,191 | 3/1982 | Yoshikawa et al. |
| 4,405,710 | 9/1983 | Balasubramanyam et al. |
| 4,419,421 | 12/1983 | Wichelhaus, et al. |
| 4,499,557 | 2/1985 | Holmberg et al. |
| 4,671,618 | 06/09/1987 | Wu et al. |
| 4,795,657 | 1/1989 | Formigoni et al. |
| 4,800,526 | 01/24/1989 | Lewis |
| 4,847,674 | 7/1989 | Sliwa et al. |
| 5,219,788 | 6/1993 | Abernathy et al. |
| 5,238,862 | 8/1993 | Blalock et al. |
| 5,272,359 | 12/21/1993 | Nagasubramanian et al. |
| 5,314,772 | 5/24/1994 | Kozicki |
| 5,315,131 | 5/1994 | Kishimoto et al. |
| 5,350,484 | 9/1994 | Gardner et al. |
| 5,360,981 | 11/1994 | Owen et al. |
| 5,500,532 | 3/19/1996 | Kozicki et al. |
| 5,512,328 | 4/1996 | Yoshimura et al. |
| 5,512,773 | 4/1996 | Wolf et al. |
| 5,726,083 | 3/1998 | Takaishi |
| 5,751,012 | 5/12/1998 | Wolstenholme et al. |
| 5,761,115 | 6/1998 | Kozicki et al. |

| | | |
|-----------|------------|---------------------|
| 5,769,277 | 8/1998 | Zahorik et al. |
| 5,814,527 | 9/29/1998 | Wolstenholme et al. |
| 5,818,749 | 10/06/1998 | Harshfield |
| 5,841,150 | 11/1998 | Gonzalez et al. |
| 5,846,889 | 12/1998 | Harbison et al. |
| 5,851,882 | 12/22/1998 | Harshfield |
| 5,869,843 | 2/9/1999 | Harshfield |
| 5,896,312 | 4/20/1999 | Kozicki et al. |
| 5,914,893 | 6/22/1999 | Kozicki et al. |
| 5,920,788 | 7/1999 | Reinberg |
| 5,998,066 | 12/1999 | Block et al. |
| 6,031,287 | 2/29/2000 | Harshfield |
| 6,072,716 | 06/06/2000 | Jacobson et al. |
| 6,077,729 | 6/2000 | Harshfield |
| 6,084,769 | 7/4/2000 | Kozicki et al. |
| 6,177,338 | 1/2001 | Liaw et al. |
| 6,117,720 | 9/2000 | Harshfield |
| 6,143,604 | 11/2000 | Chiang et al. |
| 6,236,059 | 5/2001 | Wolstenholme et al. |
| 6,297,170 | 10/2001 | Gabriel et al. |
| 6,300,684 | 10/2001 | Gonzalez et al. |
| 6,316,684 | 11/2001 | Zahorik et al. |
| 6,511,867 | 1/2003 | Lowery et al. |

In the **Other Publications** portion of the References Cited section, the USPTO made the following errors to be corrected:

“Bondarev, V.N.; Pikhitsa, P.V., A dendrite model of current instability in RgAg415. Solid State Ionics 70/71 (1994) 72-76.”

Should read

--Bondarev, V.N.; Pikhitsa, P.V., A dendrite model of current instability in RbAg₄I₅. Solid State Ionics 70/71 (1994) 72-76.--;

“Cahen, D.; Gilet, J.-M.; Schmitz, C.; Chernyak, L.; Gartsman, K.; Jakubowicz, A., Room-Temperature electric field induced creation of stable devices in CuInSe₂ Crystals, Science 258 (1992) 271-271.”

Should read

--Cahen, D.; Gilet, J.-M.; Schmitz, C.; Chernyak, L.; Gartsman, K.; Jakubowicz, A., Room-Temperature electric field induced creation of stable devices in CuInSe₂ Crystals, Science 258 (1992) 271-271.--;

“El Bouchairi, B.; Bernede, J.C.; Burgaud, P., Properties of Ag_{2-x}Se_{1+x}/n-Si diodes, Thin Solid Films 110 (1983) 107-113.”

Should read

--El Bouchairi, B.; Bernede, J.C.; Burgaud, P., Properties of Ag_{2-x}Se_{1+x}/n-Si diodes, Thin Solid Films 110 (1983) 107-113.--; and

“West, W.C.; Sieradzki, K.; Kardynal, B.; Kozicki, M.N., Equivalent circuit modeling of the Ag|As_{0.24}S_{0.36}Ag_{0.40}|Ag systems prepared by photodissolution of Ag, J. Electrochem. Soc. 145 (1998) 2971-2974.”

Should read

--West, W.C.; Sieradzki, K.; Kardynal, B.; Kozicki, M.N., Equivalent circuit modeling of the Ag|As_{0.24}S_{0.36}Ag_{0.40}|Ag systems prepared by photodissolution of Ag, J. Electrochem. Soc. 145 (1998) 2971-2974.--.

Also in Other Publications, Applicants made the following errors to be corrected:

“Kotkata, M.F.; Afif, M.A.; Labib, H.H.; Hegab, N.A.; Abdel-Aziz, M.M., Memory switching in amorphous GeSeTl chalcogenide semiconductor films, Thin Solid Films 240 (1994) 143-146.”

Should read

--Kotkata, M.F.; Afifi, M.A.; Labib, H.H.; Hegab, N.A.; Abdel-Aziz, M.M., Memory switching in amorphous GeSeTl chalcogenide semiconductor films, Thin Solid Films 240 (1994) 143-146.--;

“McHardy et al., The dissolution of metals in amorphous chalcogenides and the effects of electron and ultraviolet radiation, 20 J. Phys. C.: Solid State Phys., pp. 4055-4075 (1987)f.”

Should read

--McHardy et al., The dissolution of metals in amorphous chalcogenides and the effects of electron and ultraviolet radiation, 20 J. Phys. C.: Solid State Phys., pp. 4055-4075 (1987).--;

“Rose, M.J.; Snell, A.J.; Lecomber, P.G.; Hajto, J.; Fitzgerald, A.G.; Owen, A.E., Aspects of non-volatility in a-Si:H memory devices, Mat. Res. Soc. Symp. Proc. V 258, 1992, 1075-1080.”

Should read

--Rose, M.J.; Snell, A.J.; Lecomber, P.G.; Hajto, J.; Fitzgerald, A.G.; Owen, A.E., Aspects of non-volatility in metal/a -Si:H/metal memory devices, Mat. Res. Soc. Symp. Proc. V 258, 1992, 1075-1080.--; and

“Tranchant, S.; Peytavin, S.; Ribes, M.; Flank, A.M.; Despert, H.; Lagarde, J.P., Silver chalcogenide glasses Ag-Ge-Se: Ionic conduction and exafs structural investigation, Transport-structure relations in fast ion and mixed conductors Proceedings of the 6th Riso International symposium, Sep. 9-13, 1985.”

Should read

“Tranchant, S.; Peytavin, S.; Ribes, M.; Flank, A.M.; Despert, H.; Lagarde, J.P., Silver chalcogenide glasses Ag-Ge-Se: Ionic conduction and EXAFS structural

investigation, Transport-structure relations in fast ion and mixed conductors, Proceedings of the 6th RISO International symposium, Sep. 9-13, 1985."

In the Specification, Applicants made the following errors to be corrected:

Column 11, line 6, "900 include" should read --900 includes--; and

Column 11, line 56, "system" should read --systems--.

In the Claims, Applicants made the following error to be corrected:

Claim 12, column 13, line 33, "a erase" should read --an erase--.

Some errors were found in the application as filed by applicant but most were made by the USPTO. Please charge our Credit Card in the amount of \$100.00 covering the fee set forth in 37 CFR 1.20(a). Credit Card Payment Form SB-2038, with a signature from an authorized cardholder, is enclosed.

The errors now sought to be corrected are inadvertent errors the correction of which does not involve new matter or require reexamination.

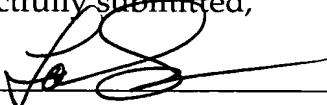
Transmitted herewith is a proposed Certificate of Correction effecting such amendment. Patentees respectfully solicit the granting of the requested Certificate of Correction.

FEB 1 2006

The Director is hereby authorized to charge any deficiency in the fees filed, asserted to be filed or which should have been filed herewith (or with any paper hereafter filed in this application by this firm) to our Deposit Account No. 04-107A duplicate copy of this paper is enclosed.

Dated: January 17, 2006

Respectfully submitted,

By 

Thomas J. D'Amico

Registration No.: 28,371

Ryan H. Flax

Registration No.: 48,141

DICKSTEIN SHAPIRO MORIN &

OSHINSKY LLP

2101 L Street NW

Washington, DC 20037-1526

(202) 785-9700

Attorneys for Applicants



Exhibit A

FEB 1 2006

DEC 02 2003

JAN 17 2006

PTO/SB/08A (10-01)

Approved for use through 10/31/2002. OMB 0651-0031
U. S. Patent and Trademark Office: U. S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

TRADE

Substitute for form 1449A/PTO

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

(use as many sheets as necessary)

Complete If Known

| | | | | | |
|-------|-----|-----------|------------|------------------------|-----------------|
| Sheet | 2 | of | 11 | Attorney Docket Number | M4065.0715/P715 |
| IN | AU1 | 3,622,319 | 11/1971 | Sharp | |
| IN | AV1 | 3,743,847 | 7/1973 | Boland | |
| IN | AW1 | 4,269,935 | 5/1981 | Masters et al. | |
| | AX1 | 4,312,938 | 1/1982 | Drexler, et al. | |
| | AY1 | 4,316,946 | 1/1982 | Masters, et al. | |
| | AZ1 | 4,320,191 | 3/1982 | Yoshikawa et al. | |
| | AA2 | 4,405,710 | 9/1983 | Balasubramanyam et al. | |
| | AB2 | 4,419,421 | 12/1983 | Wichelhaus, et al. | |
| | AC2 | 4,499,557 | 2/1985 | Holmberg et al. | |
| | AD2 | 4,671,618 | 06/09/1987 | Wu et al. | |
| | AE2 | 4,795,657 | 1/1989 | Formigoni et al. | |
| | AF2 | 4,800,526 | 01/24/1989 | Lewis | |
| | AG2 | 4,847,674 | 7/1989 | Sliwa et al. | |
| | AH2 | 5,477,567 | 1/1993 | Kersy et al. | |
| | AI2 | 5,219,788 | 6/1993 | Abernathy et al. | |
| | AJ2 | 5,238,862 | 8/1993 | Blalock et al. | |
| | AK2 | 5,272,359 | 12/21/1993 | Nagasubramanian et al. | |
| | AL2 | 5,314,772 | 5/24/1994 | Kozicki | |
| | AM2 | 5,315,131 | 5/1994 | Kishimoto et al. | |
| | AN2 | 5,350,484 | 9/1994 | Gardner et al. | |
| | AO2 | 5,360,981 | 11/1994 | Owen et al. | |
| | AP2 | 5,500,532 | 3/19/1996 | Kozicki et al. | |
| | AQ2 | 5,512,328 | 4/1996 | Yoshimura et al. | |
| | AR2 | 5,512,773 | 4/1996 | Wolf et al. | |
| | AS2 | 5,726,083 | 3/1998 | Takaishi | |
| | AT2 | 5,751,012 | 5/12/1998 | Wolstenholme et al. | |
| | AU2 | 5,761,115 | 6/1998 | Kozicki et al. | |
| | AV2 | 5,789,277 | 8/1998 | Zahorik et al. | |
| | AW2 | 5,814,527 | 9/29/1998 | Wolstenholme et al. | |
| | AX2 | 5,818,749 | 10/06/1998 | Harshfield | |
| | AY2 | 5,841,150 | 11/1998 | Gonzalez et al. | |
| | AZ2 | 5,846,889 | 12/1998 | Harbison et al. | |
| | AA3 | 5,851,882 | 12/22/1998 | Harshfield | |
| | AB3 | 5,869,843 | 2/9/1999 | Harshfield | |
| | AC3 | 5,896,312 | 4/20/1999 | Kozicki et al. | |
| | AD3 | 5,914,893 | 6/22/1999 | Kozicki et al. | |
| | AE3 | 5,920,788 | 7/1999 | Reinberg | |
| | AF3 | 5,998,066 | 12/1999 | Block et al. | |
| | AG3 | 6,031,287 | 2/29/2000 | Harshfield | |
| | AH3 | 6,072,716 | 06/06/2000 | Jacobson et al. | |
| | AI3 | 6,077,729 | 6/2000 | Harshfield | |
| | AJ3 | 6,084,796 | 7/4/2000 | Kozicki et al. | |
| | AK3 | 6,177,338 | 1/2001 | Liau et al. | |
| | AL3 | 6,117,720 | 9/2000 | Harshfield | |
| | AM3 | 6,143,604 | 11/2000 | Chiang et al. | |
| | AN3 | 6,236,059 | 5/2001 | Wolsteinholme et al. | |
| | AO3 | 6,297,170 | 10/2001 | Gabriel et al. | |
| | AP3 | 6,300,684 | 10/2001 | Gonzalez et al. | |
| | AQ3 | 6,316,784 | 11/2001 | Zahorik et al. | |

1695747 v1: 10CG3051.DOC

All but one omitted on
printed patent

VIET Q. NGUYEN
PRIMARY EXAMINER

FEB 1 2006

6/2/05

Substitute for form 1449A/B/PTO

Complete If Known 10/614,160

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet 2 of 3 Attorney Docket Number M4065.0715/P715

| | | | | |
|------|--------------|---------|------------------|------------------|
| ✓ P1 | US 5,335,219 | 8/1994 | Ovshinsky et al. | |
| ✓ Q1 | US 5,359,205 | 10/1994 | Ovshinsky | |
| ✓ R1 | US 5,341,328 | 8/1994 | Ovshinsky et al. | |
| ✓ S1 | US 5,406,509 | 4/1995 | Ovshinsky et al. | |
| ✓ T1 | US 5,414,271 | 5/1995 | Ovshinsky et al. | |
| ✓ U1 | US 5,534,711 | 7/1996 | Ovshinsky et al. | |
| ✓ V1 | US 5,534,712 | 7/1996 | Ovshinsky et al. | |
| ✓ W1 | US 5,536,947 | 7/1996 | Klersy et al. | |
| ✓ X1 | US 5,543,737 | 8/1996 | Ovshinsky | |
| ✓ Y1 | US 5,591,501 | 1/1997 | Ovshinsky et al. | |
| ✓ Z1 | US 5,596,522 | 1/1997 | Ovshinsky et al. | |
| ✓ A2 | US 5,687,112 | 11/1997 | Ovshinsky | |
| ✓ B2 | US 5,694,054 | 12/1997 | Ovshinsky et al. | |
| ✓ C2 | US 5,714,768 | 2/1998 | Ovshinsky et al. | |
| ✓ D2 | US 5,825,046 | 10/1998 | Czubatyj et al. | |
| ✓ E2 | US 5,912,839 | 6/1999 | Ovshinsky et al. | |
| ✓ F2 | US 5,933,365 | 8/1999 | Klersy et al. | |
| ✓ G2 | US 6,011,757 | 1/2000 | Ovshinsky | |
| ✓ H2 | US 6,087,674 | 7/2000 | Ovshinsky et al. | |
| ✓ I2 | US 6,141,241 | 10/2000 | Ovshinsky et al. | |
| ✓ J2 | US 6,339,544 | 1/2002 | Chiang et al. | |
| ✓ K2 | US 6,404,665 | 6/2002 | Lowery et al. | |
| ✓ L2 | US 6,429,084 | 8/2002 | Wicker | |
| ✓ M2 | US 6,437,383 | 8/2002 | Xu | |
| ✓ N2 | US 6,462,984 | 10/2002 | Xu et al. | VIET Q. NGUYEN |
| ✓ Q2 | US 6,480,438 | 11/2002 | Park | PRIMARY EXAMINER |
| ✓ P2 | US 6,487,113 | 11/2002 | Park et al. | |
| ✓ Q2 | US 6,501,111 | 12/2002 | Lowery | |
| ✓ R2 | US 6,507,061 | 1/2003 | Hudgens et al. | |
| ✓ S2 | US 6,511,862 | 1/2003 | Hudgens et al. | |
| ✓ T2 | US 6,511,867 | 1/2003 | Lowery et al. | |
| ✓ U2 | US 6,512,241 | 1/2003 | Lai | |
| ✓ V2 | US 6,514,805 | 2/2003 | Xu et al. | |
| ✓ W2 | US 6,531,373 | 3/2003 | Gill et al. | |
| ✓ X2 | US 6,534,781 | 3/2003 | Dennison | |
| ✓ Y2 | US 6,545,287 | 4/2003 | Chiang | |
| ✓ Z2 | US 6,545,807 | 4/2003 | Lowery et al. | |
| ✓ A3 | US 6,555,860 | 4/2003 | Lowery et al. | |
| ✓ B3 | US 6,563,164 | 5/2003 | Lowery et al. | |
| ✓ C3 | US 6,566,700 | 5/2003 | Xu | |
| ✓ D3 | US 6,567,293 | 5/2003 | Lowery et al. | |
| ✓ E3 | US 6,589,705 | 5/2003 | Chiang et al. | |
| ✓ F3 | US 6,570,784 | 5/2003 | Lowery | |
| ✓ G3 | US 6,576,921 | 6/2003 | Lowery | |
| ✓ H3 | US 6,586,761 | 7/2003 | Lowery | |

* Omitted

VIET Q. NGUYEN
PRIMARY EXAMINER

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

Page 1 of 5

PATENT NO. : 6,961,277
 APPLICATION NO. : 10/614,160
 ISSUE DATE : November 1, 2005
 INVENTORS : John T. Moore et al.

It is certified that errors appear in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

In the **U.S. Patent Documents** portion of the References Cited section, forty-nine patents should be added as follows:

| | | |
|-----------|------------|------------------------|
| 3,622,319 | 11/1971 | Sharp |
| 3,743,847 | 7/1973 | Boland |
| 4,269,935 | 5/1981 | Masters et al. |
| 4,312,938 | 1/1982 | Drexler, et al. |
| 4,316,946 | 1/1982 | Masters, et al. |
| 4,320,191 | 3/1982 | Yoshikawa et al. |
| 4,405,710 | 9/1983 | Balasubramanyam et al. |
| 4,419,421 | 12/1983 | Wichelhaus, et al. |
| 4,499,557 | 2/1985 | Holmberg et al. |
| 4,671,618 | 06/09/1987 | Wu et al. |
| 4,795,657 | 1/1989 | Formigoni et al. |
| 4,800,526 | 01/24/1989 | Lewis |

MAILING ADDRESS OF SENDER (Please do not use customer number below):

Thomas J. D'Amico
 DICKSTEIN SHAPIRO MORIN & OSHINSKY LLP 1
 2101 L Street NW
 Washington, DC 20037-1526

FEB 1 2006

| | | |
|-----------|------------|------------------------|
| 4,847,674 | 7/1989 | Sliwa et al. |
| 5,219,788 | 6/1993 | Abernathey et al. |
| 5,238,862 | 8/1993 | Blalock et al. |
| 5,272,359 | 12/21/1993 | Nagasubramanian et al. |
| 5,314,772 | 5/24/1994 | Kozicki |
| 5,315,131 | 5/1994 | Kishimoto et al. |
| 5,350,484 | 9/1994 | Gardner et al. |
| 5,360,981 | 11/1994 | Owen et al. |
| 5,500,532 | 3/19/1996 | Kozicki et al. |
| 5,512,328 | 4/1996 | Yoshimura et al. |
| 5,512,773 | 4/1996 | Wolf et al. |
| 5,726,083 | 3/1998 | Takaishi |
| 5,751,012 | 5/12/1998 | Wolstenholme et al. |
| 5,761,115 | 6/1998 | Kozicki et al. |
| 5,789,277 | 8/1998 | Zahorik et al. |
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| 5,818,749 | 10/06/1998 | Harshfield |
| 5,841,150 | 11/1998 | Gonzalez et al. |
| 5,846,889 | 12/1998 | Harbison et al. |
| 5,851,882 | 12/22/1998 | Harshfield |
| 5,869,843 | 2/9/1999 | Harshfield |
| 5,896,312 | 4/20/1999 | Kozicki et al. |
| 5,914,893 | 6/22/1999 | Kozicki et al. |
| 5,920,788 | 7/1999 | Reinberg |
| 5,998,066 | 12/1999 | Block et al. |
| 6,031,287 | 2/29/2000 | Harshfield |
| 6,072,716 | 06/06/2000 | Jacobson et al. |

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 DICKSTEIN SHAPIRO MORIN & OSHINSKY LLP 2
 2101 L Street NW
 Washington, DC 20037-1526

FEB 1 2006

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| 6,077,729 | 6/2000 | Harshfield |
| 6,084,769 | 7/4/2000 | Kozicki et al. |
| 6,177,338 | 1/2001 | Liaw et al. |
| 6,117,720 | 9/2000 | Harshfield |
| 6,143,604 | 11/2000 | Chiang et al. |
| 6,236,059 | 5/2001 | Wolstenholme et al. |
| 6,297,170 | 10/2001 | Gabriel et al. |
| 6,300,684 | 10/2001 | Gonzalez et al. |
| 6,316,684 | 11/2001 | Zahorik et al. |
| 6,511,867 | 1/2003 | Lowery et al. |

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"Bondarev, V.N.; Pikhitsa, P.V., A dendrite model of current instability in RgAg415. Solid State Ionics 70/71 (1994) 72-76."

Should read

--Bondarev, V.N.; Pikhitsa, P.V., A dendrite model of current instability in RbAg₄I₅. Solid State Ionics 70/71 (1994) 72-76.--;

"Cahen, D.; Gilet, J.-M.; Schmitz, C.; Chernyak, L.; Gartsman, K.; Jakubowicz, A., Room-Temperature electric field induced creation of stable devices in CuInSe₂ Crystals, Science 258 (1992) 271-271."

Should read

--Cahen, D.; Gilet, J.-M.; Schmitz, C.; Chernyak, L.; Gartsman, K.; Jakubowicz, A., Room-Temperature electric field induced creation of stable devices in CuInSe₂ Crystals, Science 258 (1992) 271-271.--;

"El Bouchairi, B.; Bernede, J.C.; Burgaud, P., Propeties of Ag_{2-x}Se_{1+x}/n-Si diodes, Thin Solid Films 110 (1983) 107-113."

Should read

--El Bouchairi, B.; Bernede, J.C.; Burgaud, P., Properties of Ag_{2-x}Se_{1+x}/n-Si diodes, Thin Solid Films 110 (1983) 107-113.--;

MAILING ADDRESS OF SENDER (Please do not use customer number below):

Thomas J. D'Amico
DICKSTEIN SHAPIRO MORIN & OSHINSKY LLP 3
2101 L Street NW
Washington, DC 20037-1526

"West, W.C.; Sieradzki, K.; Kardynal, B.; Kozicki, M.N., Equivalent circuit modeling of the Ag|As_{0.24}S_{0.36}Ag_{0.40}|Ag systems prepared by photodissolution of Ag, J. Electrochem. Soc. 145 (1998) 2971-2974."

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"Kotkata, M.F.; Afif, M.A.; Labib, H.H.; Hegab, N.A.; Abdel-Aziz, M.M., Memory switching in amorphous GeSeTi chalcogenide semiconductor films, Thin Solid Films 240 (1994) 143-146."

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"McHardy et al., The dissolution of metals in amorphous chalcogenides and the effects of electron and ultraviolet radiation, 20 J. Phys. C.: Solid State Phys., pp. 4055-4075 (1987)f."

Should read

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"Rose, M.J.; Snell, A.J.; Lecomber, P.G.; Hajto, J.; Fitzgerald, A.G.; Owen, A.E., Aspects of non-volatility in a-Si:H memory devices, Mat. Res. Soc. Symp. Proc. V 258, 1992, 1075-1080."

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"Tranchant, S.; Peytavin, S.; Ribes, M.; Flank, A.M.; Despert, H.; Lagarde, J.P., Silver chalcogenide glasses Ag-Ge-Se: Ionic conduction and exafs structural investigation, Transport-structure relations in fast ion and mixed conductors Proceedings of the 6th Riso International symposium, Sep. 9-13, 1985."

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In the Specification, the following errors are corrected:

Column 11, line 6, "900 include" should read --900 includes--; and

Column 11, line 56, "system" should read --systems--.

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Thomas J. D'Amico
DICKSTEIN SHAPIRO MORIN & OSHINSKY LLP 4
2101 L Street NW
Washington, DC 20037-1526

In the **Claims**, the following error is corrected:

Claim 12, column 13, line 33, "a erase" should read --an erase--.

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Thomas J. D'Amico
DICKSTEIN SHAPIRO MORIN & OSHINSKY LLP 5
2101 L Street NW
Washington, DC 20037-1526